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Date 10/03/02 Serial # 09/686200 Priority Application Date 10/05/02
Your Name VINH P. NGUYEN Examiner # 64821
AU 2829 Phone 703-305-4914 Room A CP4-5B20
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10-03-02A11:35 PAID

Circle: USPT DWPI EPO Abs JPO Abs IBM TDB

Other: _____

What relevant art have you found so far? Please attach pertinent citations or Information Disclosure Statements. _____

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Secondary Refs _____ Foreign Patents _____
Teaching Refs _____

What is the topic, such as the **novelty**, motivation, utility, or other specific facets defining the desired **focus** of this search? Please include the concepts, synonyms, keywords, acronyms, registry numbers, definitions, structures, strategies, and anything else that helps to describe the topic. Please attach a copy of the abstract and pertinent claims.

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Date Completed: _____
Searcher Prep/Rev Time: _____
Online Time: _____

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Patent Family _____
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Lexis-Nexis _____
WWW/Internet _____
Other _____

10/3/02

US 5,818,249

09/686200

Selected file: PLUSPAT

Search statement 2

?us5818249/pn

** SS 2: Results 1

Search statement 3

?prt fu legalall max

1/1 PLUSPAT - (C) QUESTEL-ORBIT- image
CPIM (C) Questel-Orbit
PN - US5818249 A 19981006 [US5818249]
TI - (A) Probe card having groups of probe needles in a probing test apparatus for testing semiconductor integrated circuits
PA - (A) TOKYO SHIBAURA ELECTRIC CO (JP)
IN - (A) MOMOHARA TOMOMI (JP)
AP - US71866096 19960923 [1996US-0718660]
PR - JP24953195 19950927 [1995JP-0249531]
IC - (A) G01R-001/073 G01R-031/02
EC - G01R-001/073B4
ICO - S01R-031/28E11
PCL - ORIGINAL (O) : 324762000
DT - Basic
CT - US4523144; US4799009; US4994735; US5012187; US5148103; US5525912; US5623214; US5642054
STG - (A) United States patent
AB - A probe card which can help to enhance the productivity of semiconductor integrated circuits manufacturing and to reduce the manufacturing cost thereof, and a method of probe-testing semiconductor integrated circuits by using the probe card. The probe card is designed to test semiconductor integrated circuits formed on a semiconductor wafer and arranged in rows and columns. It has groups of probe needles provided to contact semiconductor integrated circuits arranged in two columns and at least two rows. The card receives a test signal from a test device and supplies the test signal simultaneously to these semiconductor integrated circuits arranged in two columns and at least tow rows, through the groups of probe needles. It receives response signals simultaneously from the semiconductor integrated circuits through the groups of probe needles and then supplies the response signals to the tester.

1/1 LGST - (C) LEGSTAT
PN - US 5818249 [US5818249]
AP - US 718660/96 19960923 [1996US-0718660]
DT - US-P
ACT - 19960923 US/AE-A
APPLICATION DATA (PATENT)
{US 718660/96 19960923 [1996US-0718660]}
- 19960923 US/AS02
ASSIGNMENT OF ASSIGNOR'S INTEREST
KABUSHIKI KAISHA TOSHIBA SAIWAI-KU 72 HORIKAWA-CHO KAWASAKI-SHI, JAPAN
* MOMOHARA, TOMOMI : 19960912
- 19981006 US/A
PATENT

10/3/02

US 5,818,249

09/686200

- 20001226 US/RF
REISSUE APPLICATION FILED
20001005
- 20010206 US/RF
REISSUE APPLICATION FILED
20001005
- 20020507 US/RF
REISSUE APPLICATION FILED
20001005
UP - 2002-20

1/1 CRXX - (C) CLAIMS/RRX

AN - 3051183
PN - 5,818,249 D 19981006 [US5818249]
PA - Toshiba Corp JP
PT - E (Electrical)
ACT - 20001005 REISSUE REQUESTED
ISSUE DATE OF O.G.: 20001226
REISSUE REQUEST NUMBER: 09/686200
EXAMINATION GROUP RESPONSIBLE FOR REISSUEPROCESS: 2858

Reissue Patent Number:

- 20001005 REISSUE REQUESTED
ISSUE DATE OF O.G.: 20010206
REISSUE REQUEST NUMBER: 09/686200
EXAMINATION GROUP RESPONSIBLE FOR REISSUEPROCESS: 2858

Reissue Patent Number:

- 20001005 REISSUE REQUESTED
ISSUE DATE OF O.G.: 20020507
REISSUE REQUEST NUMBER: 09/686200
EXAMINATION GROUP RESPONSIBLE FOR REISSUEPROCESS: 2858

Reissue Patent Number:

UP - 2000-52
UACT- 2002-05-07

1/3 PAST - (C) Thomson Derwent

AN - 200219-001721
PN - 5818249 A [US5818249]
DT - A (UTILITY)
OG - 2002-05-07
CO - REA
ACT - REISSUE APPLICATION FILED
SH - REISSUE APPLICATION FILED

2/3 PAST - (C) Thomson Derwent

AN - 200106-001128
PN - 5818249 A [US5818249]
DT - A (UTILITY)
OG - 2001-02-06

10/3/02

US 5,818,249

09/686200

CO - REA
ACT - REISSUE APPLICATION FILED
SH - REISSUE APPLICATION FILED

3/3 PAST - (C) Thomson Derwent
AN - 200052-001230
PN - 5818249 A [US5818249]
DT - A (UTILITY)
OG - 2000-12-26
CO - REA
ACT - REISSUE APPLICATION FILED
SH - REISSUE APPLICATION FILED

Search statement 3

?file inpadoc

Selected file: INPADOC

Search statement 2

?fam us5818249/pn

1 Patent Groups
** SS 2: Results 4

Search statement 3

?famstate nonstop

1/4 INPADOC - (C) INPADOC
PN - JP 3135825 B2 20010219 [JP3135825]
IN - MOMOHARA TOMOYOSHI
PA - TOKYO SHIBAURA ELECTRIC CO
AP - JP 249531/95-A 19950927 [1995JP-0249531]
PR - JP 249531/95-A 19950927 [1995JP-0249531]
IC - H01L-021/66

2/4 INPADOC - (C) INPADOC
PN - JP 9092694 A2 19970404 [JP09092694]
TI - PROBE CARD AND PROBE TEST METHOD FOR SEMICONDUCTOR INTEGRATED CIRCUIT
USING THE PROBE CARD
IN - MOMOHARA TOMOYOSHI
PA - TOKYO SHIBAURA ELECTRIC CO
AP - JP 249531/95-A 19950927 [1995JP-0249531]
PR - JP 249531/95-A 19950927 [1995JP-0249531]
IC - H01L-021/66; G01R-001/073; G01R-031/26

3/4 INPADOC - (C) INPADOC
PN - TW 409335 B 20001021 [TW-409335]
TI - PROBE CARD AND PROBE TEST METHOD FOR SEMICONDUCTOR INTEGRATED CIRCUIT
USING THE PROBE CARD
IN - MOMOHARA TOMOMI [JP]

10/3/02

US 5,818,249

09/686200

PA - TOKYO SHIBAURA ELECTRIC CO [JP]
AP - TW 85112468/96-A 19961012 [1996TW-0112468]
PR - JP 249531/95-A 19950927 [1995JP-0249531]
IC - H01L-021/66

4/4 INPADOC - (C) INPADOC
PN - US 5818249 A 19981006 [US5818249]
TI - PROBE CARD HAVING GROUPS OF PROBE NEEDLES IN A PROBING TEST APPARATUS
FOR TESTING SEMICONDUCTOR INTEGRATED CIRCUITS
IN - MOMOHARA TOMOMI [JP]
PA - TOKYO SHIBAURA ELECTRIC CO [JP]
AP - US 718660/96-A 19960923 [1996US-0718660]
PR - JP 249531/95-A 19950927 [1995JP-0249531]
IC - G01R-031/02; G01R-001/073

1/1 LEGALI - (C) LEGSTAT
PN - US 5818249 [US5818249]
AP - US 718660/96 19960923 [1996US-0718660]
DT - US-P
ACTE- 19960923 US/AE-A
APPLICATION DATA (PATENT)
{US 718660/96 19960923 [1996US-0718660]}
- 19960923 US/AS02
ASSIGNMENT OF ASSIGNOR'S INTEREST
KABUSHIKI KAISHA TOSHIBA SAIWAI-KU 72 HORIKAWA-CHO KAWASAKI-SHI, JAPAN
* MOMOHARA, TOMOMI : 19960912
- 19981006 US/A
PATENT
- 20001226 US/RF
REISSUE APPLICATION FILED
20001005
- 20010206 US/RF
REISSUE APPLICATION FILED
20001005
- 20020507 US/RF
REISSUE APPLICATION FILED
20001005
UP - 2002-20

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Terms: **patno=5818249** ([Edit Search](#))

08718660 () 5818249 October 6, 1998

UNITED STATES PATENT AND TRADEMARK OFFICE GRANTED PATENT
5818249

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October 6, 1998

Probe card having groups of probe needles in a probing test apparatus for testing
semiconductor integrated circuits

REISSUE: October 5, 2000 - Reissue Application filed Oct. 5, 2000 (O.G. Feb. 6, 2001) Ex.
Gp.: 2858; Re. S.N. 09/686,200 Reissue Application filed Oct. 5, 2000 (O.G. Dec. 26, 2000)
Ex. Gp.: 2858; Re. S.N. 09/686,200 February 6, 2001; October 5, 2000 - Reissue Application
filed Ex. Gp.: 2858; Re. S.N. 09/686,200 May 7, 2002

INVENTOR: Momohara, Tomomi, Yokohama, JPX

APPL-NO: 08718660 ()

FILED-DATE: September 23, 1996

GRANTED-DATE: October 6, 1998

PRIORITY: September 27, 1995 - 7-249531, Japan (JP)

ASSIGNEE-AT-ISSUE: Kabushiki Kaisha Toshiba, Tokyo, JPX

ASSIGNEE-AFTER-ISSUE: September 23, 1996 - ASSIGNMENT OF ASSIGNOR'S INTEREST
(SEE DOCUMENT FOR DETAILS)., KABUSHIKI KAISHA TOSHIBA SAIWAI-KU 72
HORIKAWA-CHO KAWASAKI-SHI, JAPAN,, Reel and Frame Number: 008237/0461

LEGAL-REP: Loeb & Loeb LLP

PUB-TYPE: October 6, 1998 - Utility Patent having no previously published pre-grant
publication (A)

PUB-COUNTRY: United States (US)

US-MAIN-CL: 324#762

SEARCH-FLD: 324##762 , 324##731 , 324##758 , 324##760 , 324##754 , 437##8

IPC-MAIN-CL: G 01R031#2

IPC ADDL CL: G 01R001#73

PRIM-EXMR: Karlsen, Ernest F.



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